

FIG. 1

10

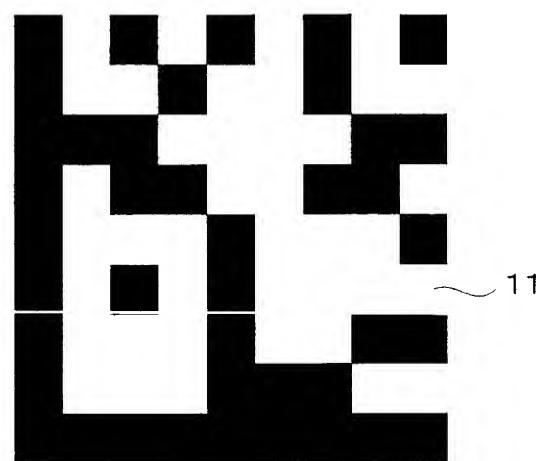
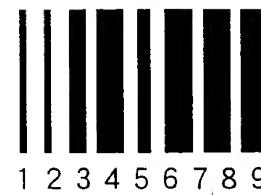


FIG. 2

20

21



23

FIG. 3

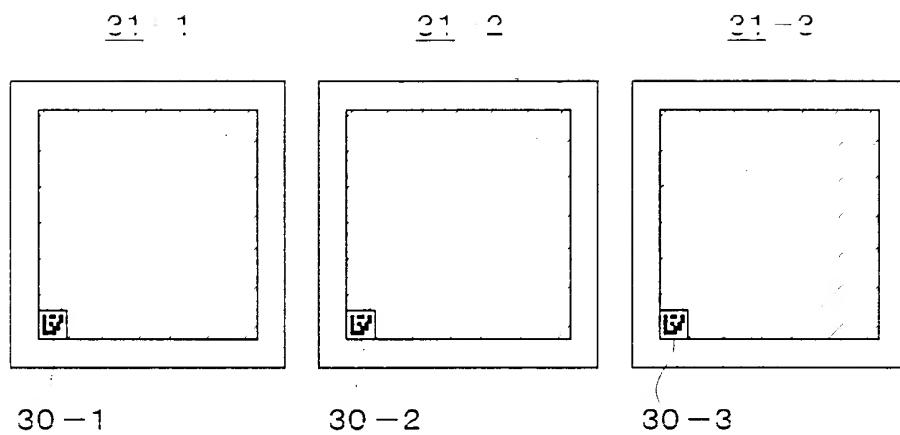


FIG. 4

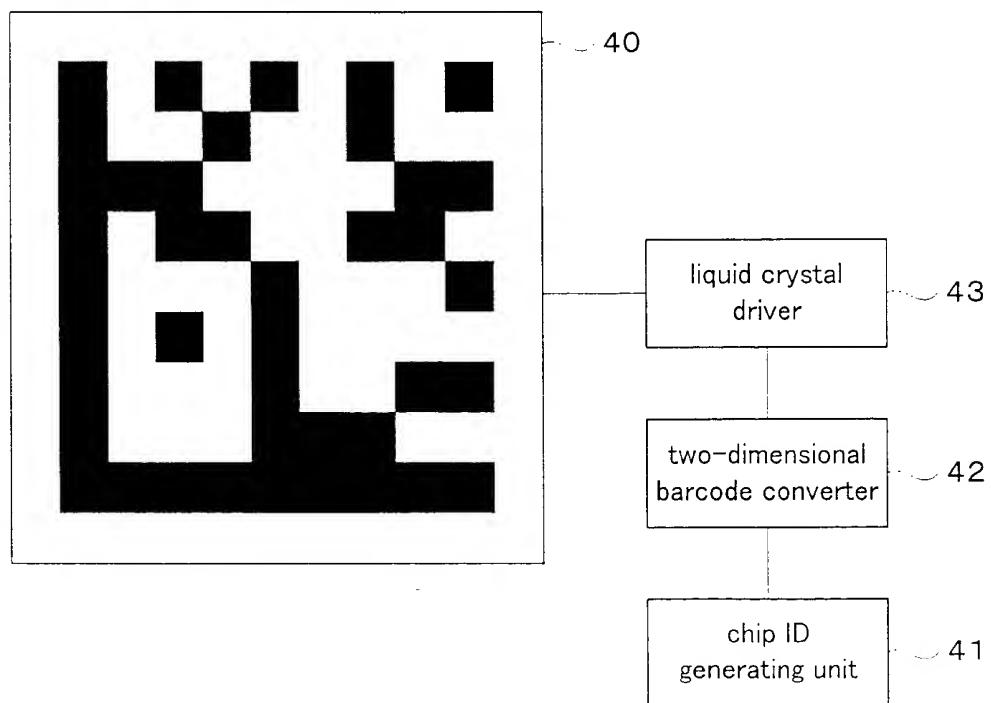


FIG. 5

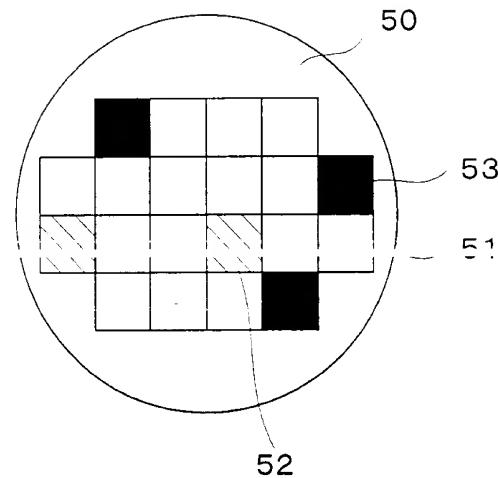


FIG. 6

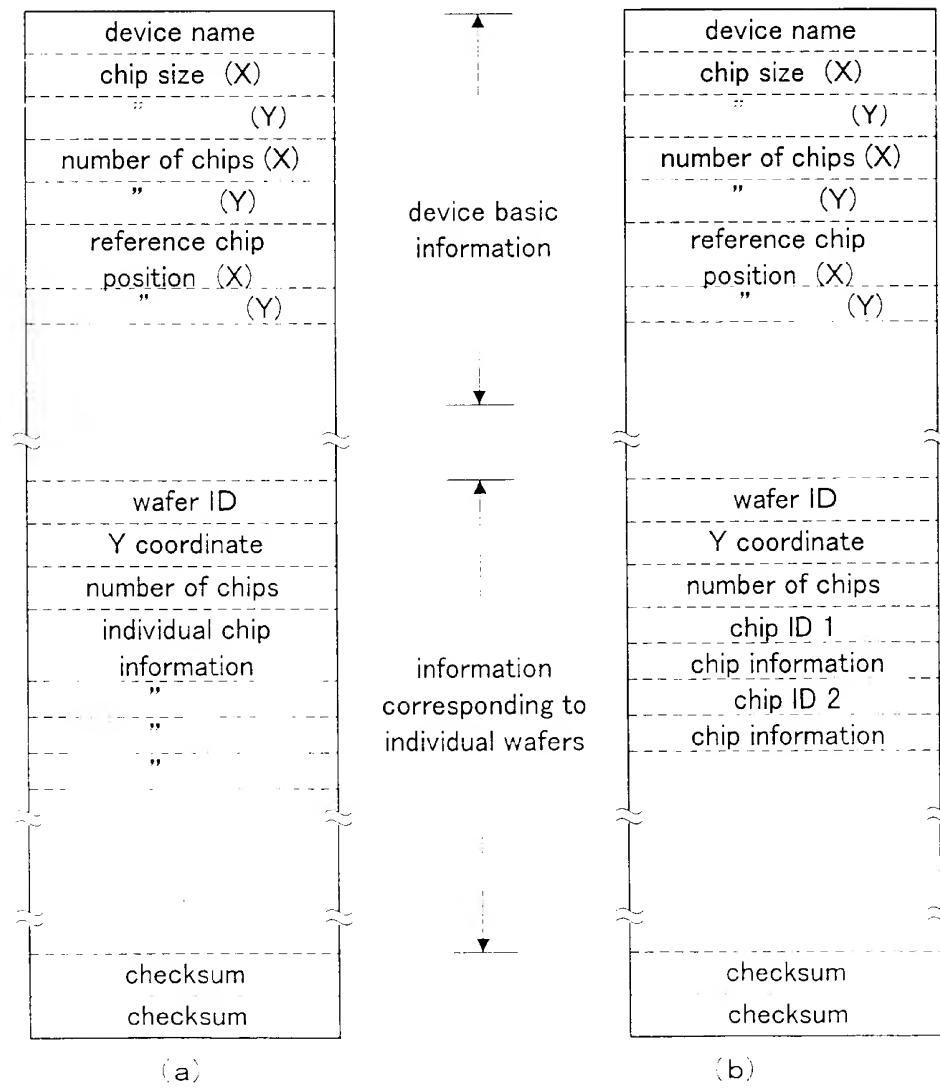


FIG. 7

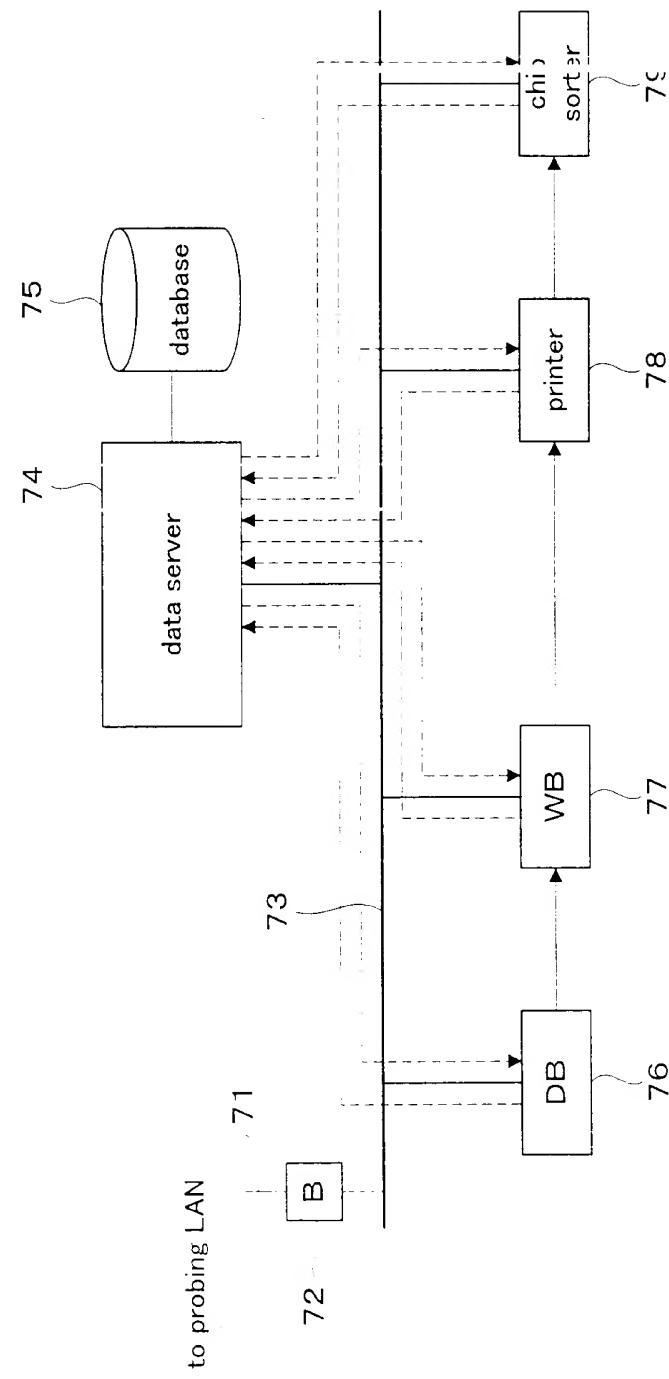


FIG. 8

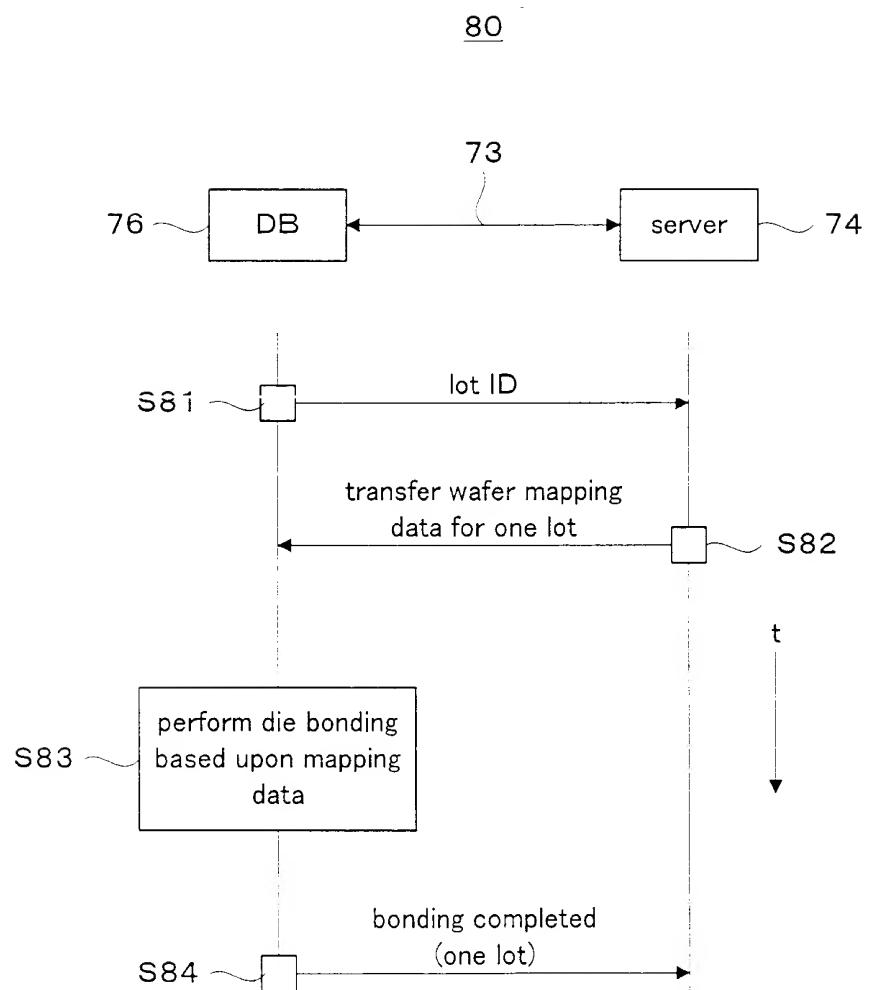


FIG. 9

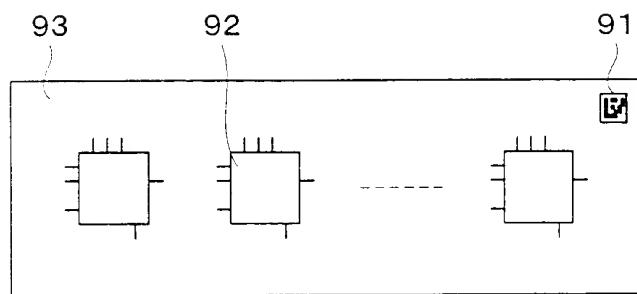


FIG. 11

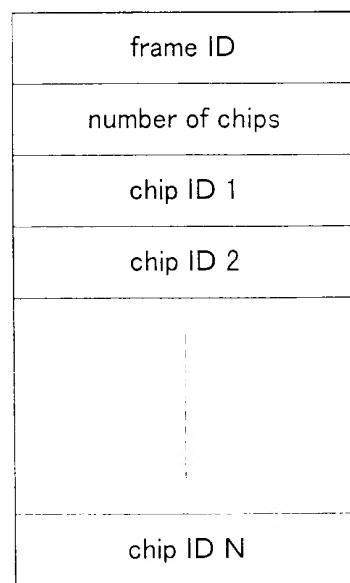


FIG. 10

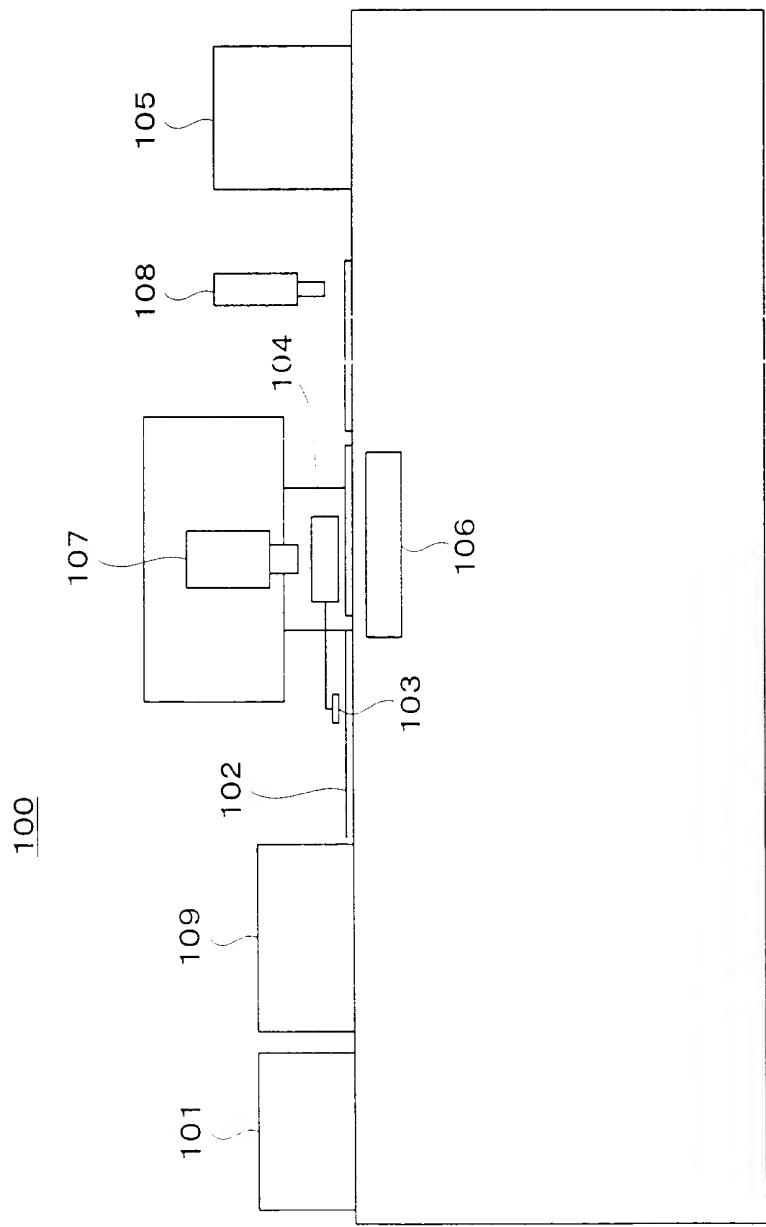


FIG. 12

chip ID * * * *	product code	* * * * *		
	wafer process flow No.	* * * *		
probing category code * *				
process	device type	manufacturing conditions	processing date	processing device collected data
die bonding	* * *	bonding conditions * *	* * *	* *
wire bonding	* * *	wiring pattern * *	* * *	* *
printing	* * *	printing pattern * *		

FIG. 13

130

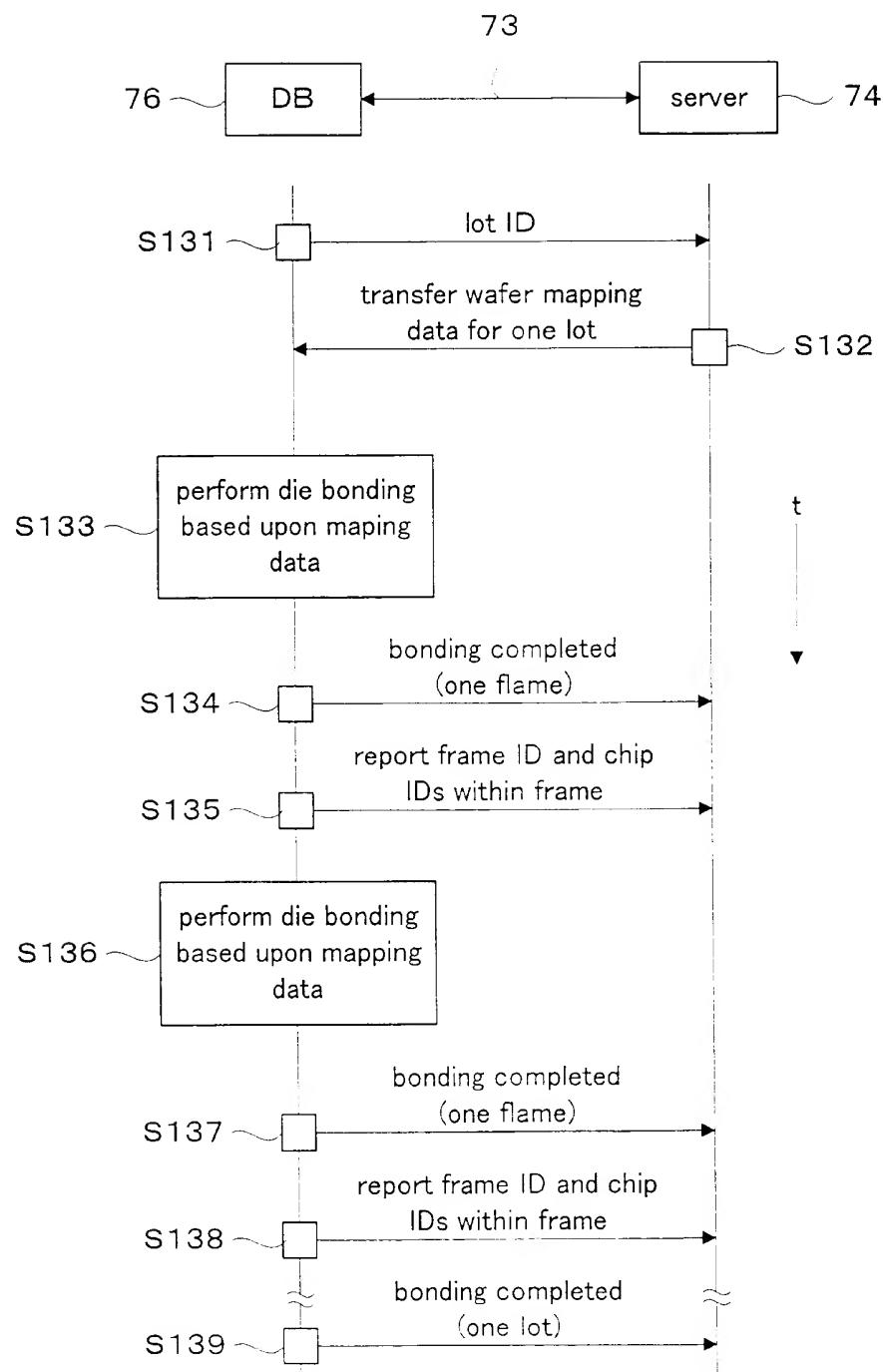


FIG. 14

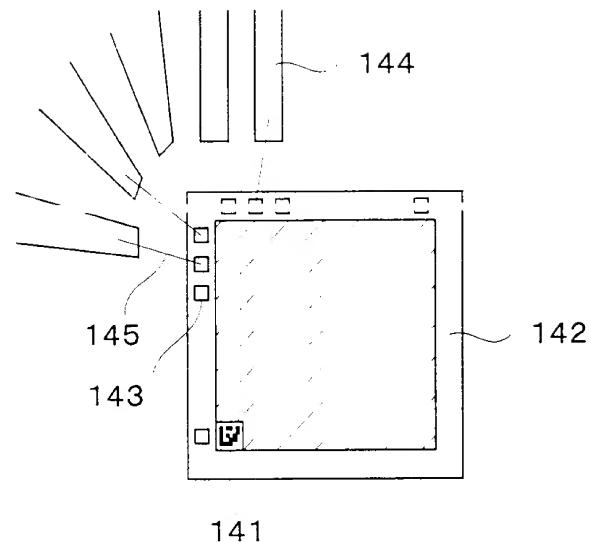


FIG. 15

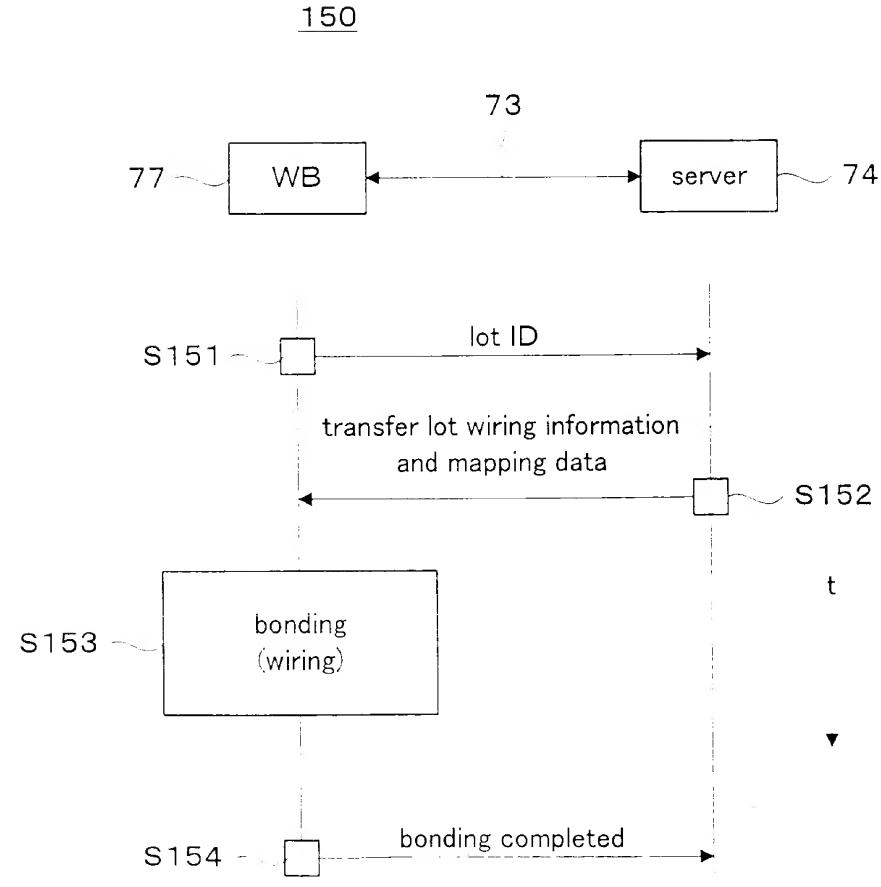


FIG. 16

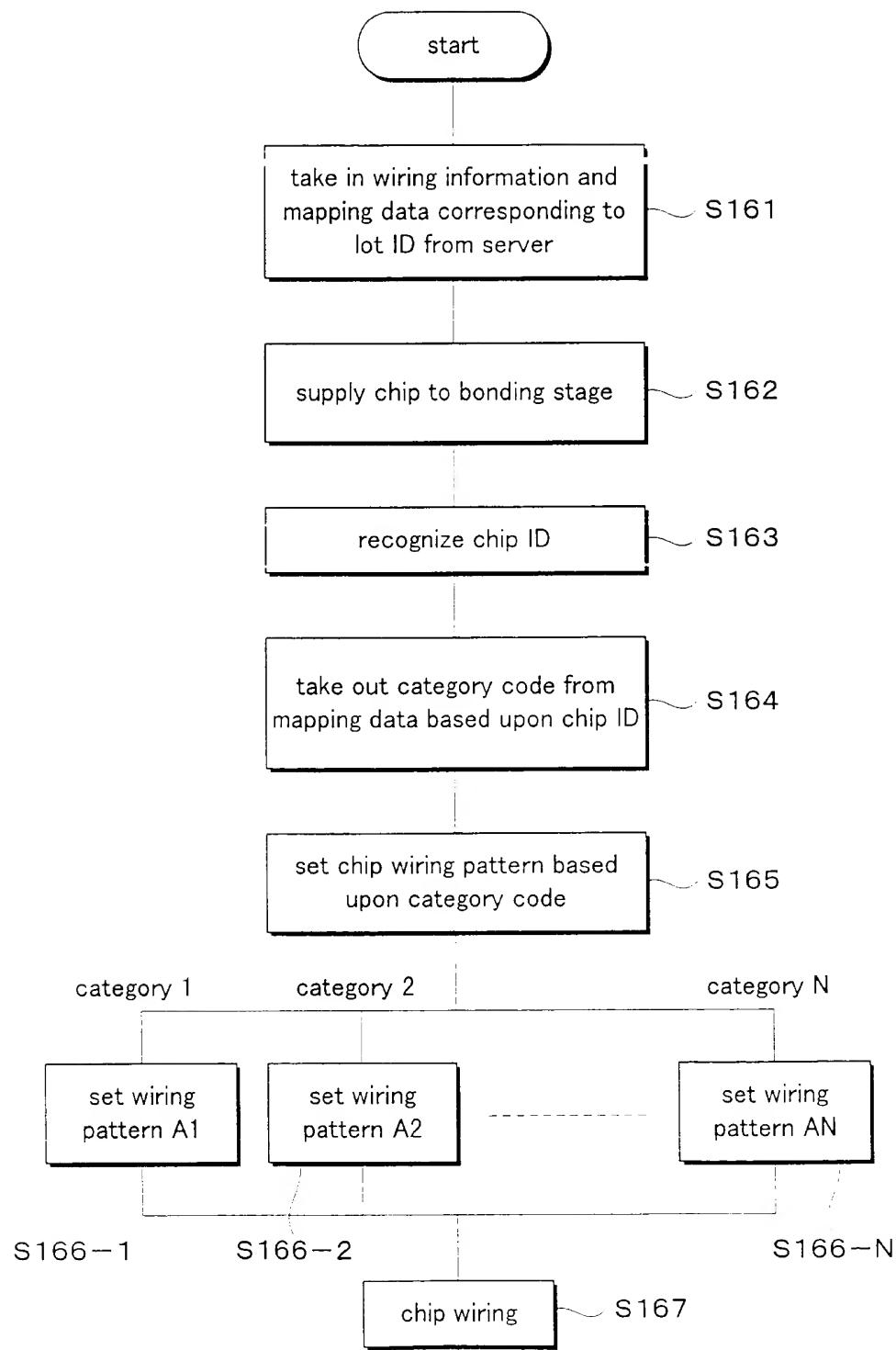


FIG. 17

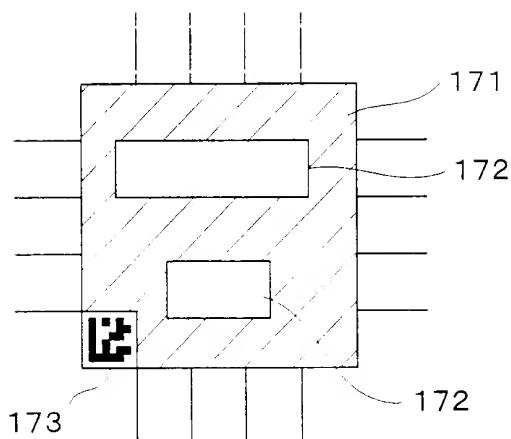


FIG. 18

180

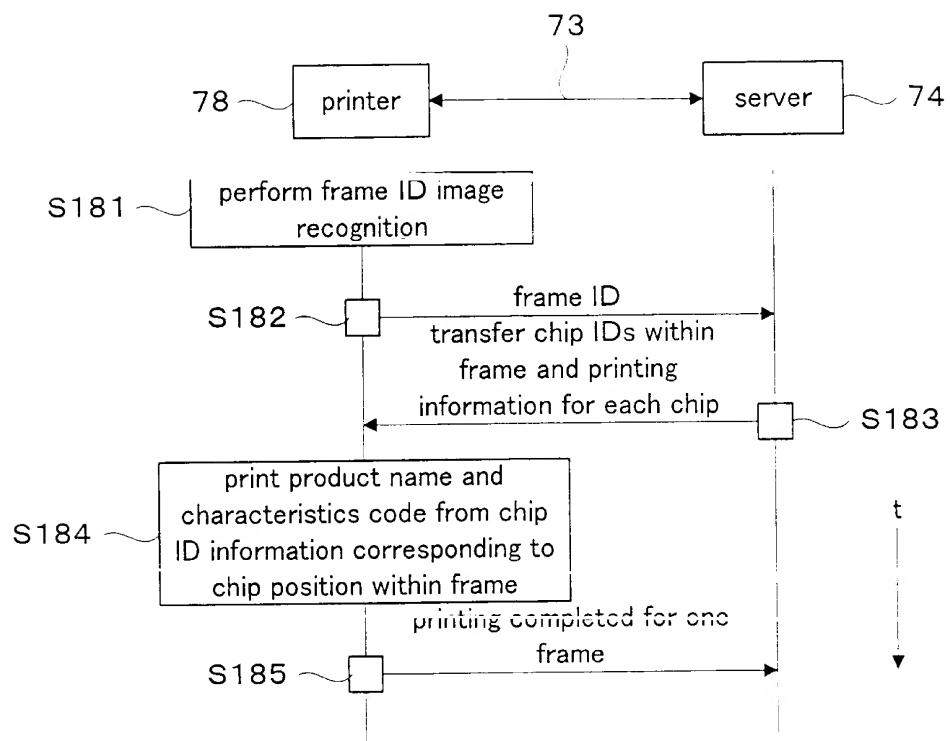


FIG. 19

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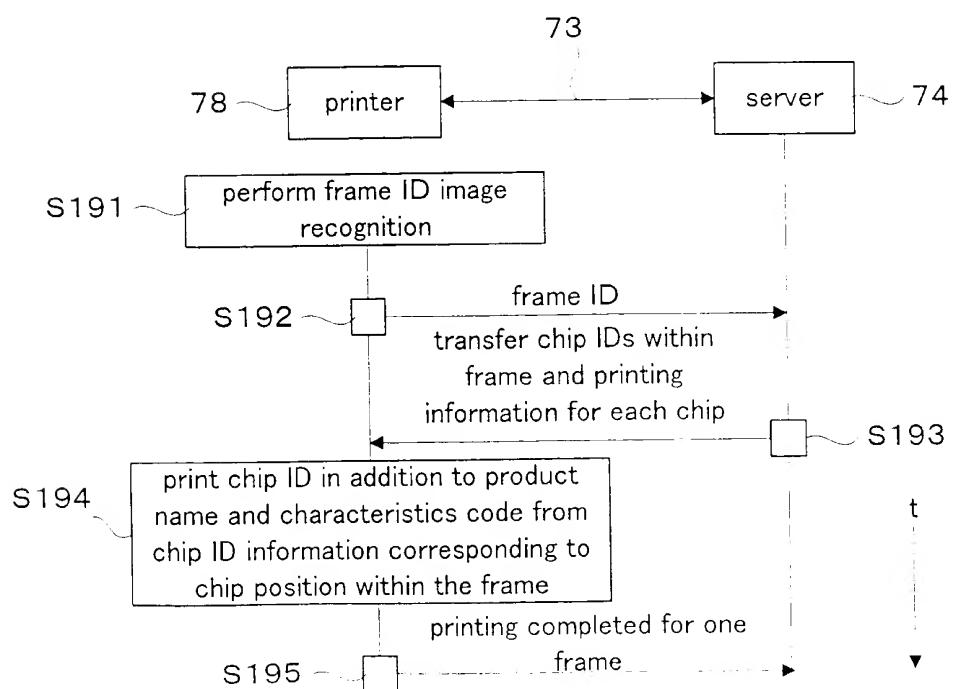


FIG. 20

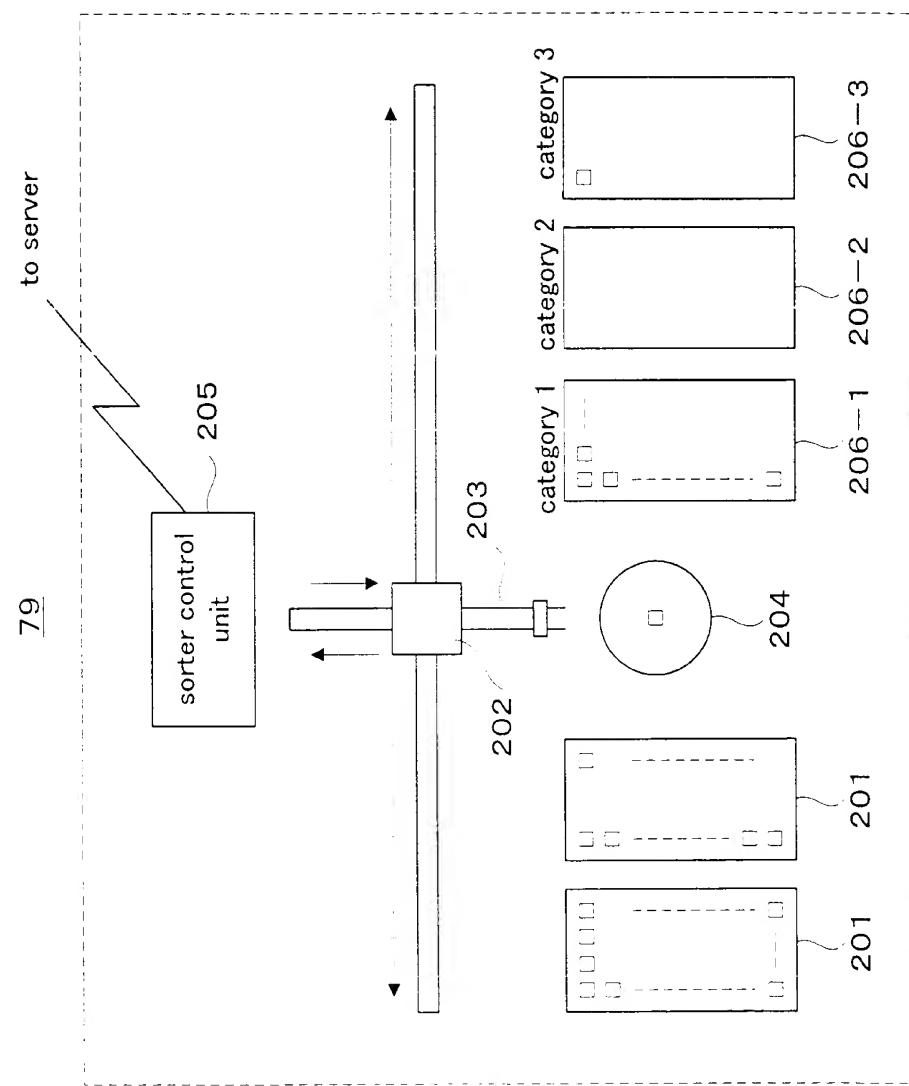


FIG. 21

Chip ID information table

1. wafer process
processing history information
2. assembly process
processing history information
3. text data
*probing
*chip status

FIG. 22

Chip ID information table

1. wafer process
processing history information
2. assembly process
processing history information
3. text data
*probing
*chip status
4. shipping information
shipping destination
packaging status
shipping data
5. post-shipment field
claim information
claim history